

## PG101 WIS Wafer level test with spherical system



The PG101WIS is integrated manual probe platform with spectrophotometer system to perform a photoelectric materials analysis for LED, PD, Vcsel, laser diode etc...The system has good cost-performance ratio for your application and research.

### Spectrophotometer Specification

Item	Range	Accuracy
Peak Wavelength( $\lambda_p$ )	380~780nm	$\pm 0.5$ nm
Dominate Wavelength( $\lambda_d$ )	380~780nm	$\pm 0.5$ nm
Luminous Flux (lm)	1lm~250.000lm	$\pm 4\%$
	repeatability	$\pm 0.2\%$
Color Temperature	1000K~10.000K	Follow (x,y)
Chromaticity Coordinates	CIE 1931 (x,y)	$\pm 0.003$
	repeatability	$\pm 0.2\%$
Correlated Color Temperature	CCT	Follow (x,y)
FWHM	0~200nm	$\pm 0.5$ nm
Purity	100%	$\pm 5\%$
CRI(R1-R15)	0-100%	$\pm 3\%$

### Features

- Compact size
- Weight light
- Electro-Optics application
- Light intensity/Wave length
- Measurement for LED/Vcsel/LD/PD
- Ideal for 4 inch wafer or less

### Prober Specification

- 4 inch Ni coating metal vacuum chuck
- Vacuum lines for different sample size
- Sample size: 5mm\*5mm-4 inch
- Platen for 4 sets of Micropositioner
- 10um moving resolution micro X-Y stage with Chuck

### Option

- Chuck theta adjustable
- Hot chuck 25-150°C $\pm 1^\circ$ C
- High voltage probe
- Low current/Capacitance probe
- Device holder
- PCB holder
- Vibration free table
- Vacuum pump
- Shielding box

